Technical Report

## Practical Methods for Detecting Peaks in Auger Electron Spectroscopy and X-Ray Photoelectron Spectroscopy

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(Received: September 25, 2007; Accepted: December 7, 2007)

Three kinds of peak detecting algorithms for AES and XPS spectrum are proposed. These peak detecting methods are composed of three stages of algorithms: rough estimation of the background; direct calculation of the peak and background relation at the candidate peak; and application of the second derivative curve. This report provides concrete methods of finding peaks in a measured spectrum of surface analysis based on an empirical investigation of how to detect significant signals among faint ones. Algorithms and characteristics of the respective peak detecting methods are discussed.

#### 1. Introduction

The presence of peaks in the spectrum obtained from the original data must first be determined as the primary source of information, when a qualitative or quantitative analysis is carried out for AES and XPS, especially when making a decision on the presence of elements.

Surface chemical analysts use many different methods to detect peaks in data, but as there may be no uniquely defined perfect method, analysts sometimes pick peaks visually. However, since scientists often rely on computers to perform basic analyses of data, scientists and instrument manufactures have developed their own peak detecting algorithms [1]. Their algorithms and techniques rely on straightforward methods for calculating the peak locations.

There are different ways to write algorithms to detect peaks, but their algorithms are not sufficiently clarified, nor do they always work for poorly resolved peaks. Since each method has relative merits, it is desirable for analysts to understand each algorithm and its performance in order to select the best or alternate method.

It is also important to track accurately and verify what has been done to the data. Data files processed by programs should leave a comprehensive audit trail to ensure traceability. To satisfy the strictest compliance standards, the appropriate audit trail should contain a complete description of the processing methods and equations applied to the data as well as program version.

This report provides concrete methods of finding peaks in a measured spectrum of surface analysis based on an empirical investigation of how to detect significant signals among faint ones. The purpose of this report is to give analysts a practical guide for finding peaks in a spectrum using their algorithms.

In the activity that relates to the international standardization in ISO TC201-SC3-WG4 (Surface Chemical Analysis-Data Management and Treatment- Peak Detection), three peak detecting methods have been proposed and discussed.

#### 2. General considerations regarding peak detection

Described herein are basic data processing methods and specific aspects of detecting peaks such as peak detection criteria, the detection of poorly resolved peaks, small and broad peaks and overlapped peaks with valleys.

#### 2.1. Peak detection criteria

In order to define peak detection criteria, it should be assumed that the data obtained with a pulse-counting detector will obey statistical theory based on the Poisson distribution. Then, empirical conditions for the detection criteria can be naturally defined, and concrete techniques for practical peak detection methods can be obtained.

"Peak detection criteria" is specifically referred to empirically determined criteria for detecting peaks in AES and XPS spectra, which are normally acquired without distortion due to instrument error, except for random noise.

Strictly speaking, the peak in question may have different background intensities on its lower and higher energy sides. In such a case, the presence of the peak should be decided by setting conditions on both sides of the peak independently. However, this makes it too complex to develop the argument further, so sometimes the peak is assumed to have a nearly flat or linear background on both sides, and it is further assumed that the peak can be decided by a single decision inequality.

#### 3. Peak detection methods

The proposed peak detection methods are composed of three kinds of algorithms: for making a rough estimation of the background, for using the second derivative curve, and for directly calculating the peak and background relation at the candidate peak. The algorithms of these three methods are described in the following.

## 3.1. Peak detection using rough estimation of spectrum background

This method firstly assumes that the background curve of a spectrum is generally gentle and the total spectrum region containing peaks is much narrower than the region without peaks, and then makes a rough estimation of the background intensity for each point of the spectrum.

As the background intensity changes rather gently compared with the intensity near the peak, it can be approximately expanded by using the 2m+1 points of data which cover the region with several times of the typical full width at half maximum of the peak,<sup>\*</sup> w. The number

of averaging points, 2m+1, is selected so as to be equal to several times of the number of points in the typical full width at half maximum of the average peak of the spectrum.

The background  $b_i$  (*i*=1,*T*) (where, *T* is the total sampling points) then can be approximately written by using the given spectrum data  $y_i$  as follows:

$$b_i = \sum_{j=-m}^m h_j y_{i+j} \tag{1}$$

where  $h_j$  is the coefficient of the simple moving average, and is expressed as  $h_j=1/(2m+1)$ .

The variance of  $b_i$  is expressed by using such expansion as follows [2]:

$$\sigma_{bi}^{2} = \sum_{j=-m}^{m} h_{j}^{2} (Var)_{i+j} + \sum_{j=-m}^{m} \sum_{l\neq j}^{m} h_{j} h_{l} (Cov)_{[i+j],[i+j]}$$
(2)

where  $(Var)_{i+j}$  is the variance of  $y_{i+j}$  and  $(Cov)_{[i+j],[j+l]}$  the covariance of  $y_{i+j}$  and  $y_{j+l}$ . If the random nature of the spectrum data  $y_i$  which obeys statistical theory based on the Poisson distribution is assumed,

$$\left(Var\right)_{i+j} = y_{i+j} \tag{3}$$

Further, each  $y_i$  is measured independently, and may have no correlation with each other, then:

$$(Cov)_{[i+j],[j+l]} = 0$$
 (4)

Then, the variance of  $b_i$  can be approximately expressed as

$$\sigma_{bi}^{2} = \sum_{j=-m}^{m} h_{j}^{2} y_{i+j} = \frac{1}{(2m+1)^{2}} \sum_{j=-m}^{m} y_{i+j}$$
(5)

If the variance of  $n_i = y_i \cdot b_i$  is defined as  $\sigma_{ni}^2$ , it can be estimated as follows:

$$\sigma_{ni}^{2} = \sigma_{yi}^{2} + \sigma_{bi}^{2} = y_{i} + \frac{1}{(2m+1)^{2}} \sum_{j=-m}^{m} y_{i+j}$$
(6)

Therefore, the final inequality to judge a peak is given by using the critical value  $k\approx 2\sim 3$ ,

<sup>&</sup>lt;sup>\*</sup>The typical full width at half maximum of the average peak: Generally, spectra acquired with an instrument such as AES or XPS include peaks with certain range of FWHM. "The FWHM of the average peak" represents the approximate value for the FWHMs of such peaks. For example, it is 20 eV for AES and 10 eV for XPS, which may be allowed to adopt as default values.

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$$n_{i} > k\sigma_{ni} = k\sqrt{y_{i} + \frac{1}{(2m+1)^{2}} \sum_{j=-m}^{m} y_{i+j}}$$
(7)

or, in a more familiar expression,

$$y_i > b_i + k\sigma_{ni} \tag{8}$$

where  $b_i + k\sigma_{ni}$  defined as the noise threshold curve. The local maximum  $y_i$  satisfying the inequality Eq. (8) is regarded as a peak (see Fig. 1.).

Furthermore, in order to apply this procedure more effectively for the practical situations, some exceptional cases should be taken into consideration. In one of such situations, there is the case that some especially broad peaks in the spectrum do not satisfy inequality Eq. (8).

In order to cope with these situations, a peak, which satisfies the following inequality, is included if its  $S_i^*$  is greater than a certain value  $S_{i0}^{**}$ .

$$S_i > S_{i0} \tag{9}$$

The approximate value of  $S_{i0}$  is roughly estimated by assuming it as an ideal triangle peak with the typical full

width w at half maximum of the peak and height  $k\sigma_{ni}$ (noise threshold curve), then its peak area S would be,  $1/2 \times 2 \times w \times k\sigma_{ni} = w k\sigma_{ni}$ .

$$S_{i0} = k\sigma_{ni}w \tag{10}$$

In fact, if the peak area Si is greater than the value above, the peak is found to be real one in most of the cases [3].

For poorly resolved peaks with deep valleys, the following data processing is effective. If the spectrum has plural peaks above noise threshold curve  $k\sigma_{ni}$  and valleys that do not cross the noise threshold curve, and if valley depth  $D^{***}$  of the minor local maximum in the spectra exceeds the noise fluctuation  $k\sigma_{ni}$ , the peaks are regarded as real.

$$|D| > k\sigma_{ni} \tag{11}$$

By adding such exceptional cases, this peak-detection method becomes effective in the actual spectrum processing.



Fig. 1. Schematic diagram of  $y_i$ ,  $b_i$  and  $b_i + k\sigma_{ni}$ .

<sup>\*\*</sup> $S_{i0}$ : This is obtained as the area of the triangle (typical noise peak) by multiplication of typical FWHM and  $k\sigma_{ni}$ .

 $S_i$ : The software evaluates the (*i*-th) peak area by summing the difference from the measured spectrum value to the background value at every successive position while the difference is positive.

<sup>\*\*\*</sup> Valley depth, *D*: The software evaluates the valley depth by searching a local maximum that exceeds the deviation of the noise height and, just after finding the local maximum, a local minimum that exceeds the deviation of the noise height, and calculating the difference between the local maximum and the local minimum.

## **3.2.** Peak detection using threshold curve of second derivative

This method has the same effect as subtracting the background from the spectrum, by making use of the second derivatives. And because it has no arbitrariness in the background subtracting procedure, it may be a relatively convenient algorithm when we use it with the aid of computers.

By making use of the moving polynomial approximation procedure (Savitzky-Golay method), it is possible to calculate the second derivative spectrum  $d_i$  from the original spectrum  $y_i$  as follows:

$$d_{i} = \sum_{j=-n}^{n} g_{j} y_{i+j}$$
(12)

where,  $g_i$  (j = -n, n) is the Savitzky-Golay coefficients for the second derivative, and if 2n+1 points of data cover roughly the half width of the typical peak, the obtained second derivative will faithfully represent the true second derivative curve. If it is expressed as mentioned above, the variance  $\sigma_i^2$  of  $d_i$  can be obtained as follows:

$$\sigma_i^2 = \sum_{j=-n}^n g_j^2 (Var)_{i+j} + \sum_{j=-nl\neq j}^n g_j g_l (Cov)_{[i+j],[i+j]}$$
(13)

where  $(Var)_{i+j}$  is the variance of  $y_{i+j}$  and  $(Cov)_{[i+j],[j+l]}$  the covariance of  $y_{i+j}$  and  $y_{j+l}$ . Again, if we assume the random nature of the spectrum data  $y_i$  which obeys statistical theory based on the Poisson distribution, then:

$$\left(Var\right)_{i+i} = y_{i+i} \tag{14}$$

Further, each  $y_i$  is measured independently, and may have no correlation with each other, then:

$$(Cov)_{[i+j],[j+l]} = 0$$
 (15)

Thus, the variance  $\sigma_i^2$  of  $d_i$  can be approximately calculated as follows:

$$\sigma_i^2 = \sum_{j=-n}^n g_j^2 y_{i+j}$$
(16)

As the peak in the spectrum corresponds to the local minimum of the spectrum, we judge the peak is real one if the local negative minimum  $d_{\min}$  is less than (in absolute values, greater than) its noise fluctuation.

Therefore, for the peak judge inequality, if the following inequality Eq. (17) is satisfied, we admit the peak is detected at the position that gives  $d_{\min}$  in the second derivative if the following inequality is satisfied [3,4],

$$d_{\min} < k\sigma_i \tag{17}$$

where  $k\sigma_i$  defined as the noise threshold curve.



Fig. 2. Schematic diagram of a peak position, second derivative curve and threshold noise curve.

# **3.3.** Peak detection by directly calculating peak and background relations at the candidate peaks

In this method, the candidate peaks are detected by the second derivative treatment and judged by comparison with criteria.

In this case, the candidate peaks are detected following the steps described below:

- Calculate the second derivative curve (e.g. by using Savitzky-Golay method [4]) and calculates the standard deviation (*σ<sub>i</sub>*) for the second derivative curve.
- (2) Pick up the candidate peak positions satisfying the local minimum (nagative value) of the second derivative curve is negative.
- (3) Let p be a candidate peak position, and w be the typical full width at half maximum of the peak<sup>\*</sup> in the original spectrum, where w is usually given in the peak detection condition (see Fig. 3.). If there exists a positive local maximum at x=p<sub>1</sub> in the second derivative spectral range, p-3w≤x1</sub>=p-3w is regarded as the position), the position, p<sub>1</sub> is regarded as a midway one to the left-side background, and furthermore if there exists a local minimum in the smoothed spectrum or a zero cross position in the second derivative spectrum at x=q<sub>1</sub> in the spectral range, p<sub>1</sub>-2w≤x<p<sub>1</sub> in the nearest candidate peak (if

does not exist, the position,  $q_1=p_1-2w$  is regarded as the position), the distance,  $l_1=p-q_1$  corresponds to the left-side background position  $p-l_1$  with intensity  $B_1$ .

- (4) Likewise, If there exists a positive local maximum at x in the second derivative spectral range, p<x≤p+3w in the nearest candidate peak (if does not exist, the position, p<sub>2</sub>=p+3w is regarded as the position), the position, x=p<sub>2</sub> is regarded as a midway one to the right-side background, and furthermore if there exists a local minimum peak position in the smoothed spectrum or a zero cross position in the second derivative spectrum in the spectral range, p<sub>2</sub>≤x<p<sub>2</sub>+2w in the nearest candidate peak (if does not exist, the position, q<sub>2</sub>=p<sub>2</sub>+2w is regarded as the position), the distance, l<sub>2</sub>=q<sub>2</sub>-p corresponds to the right-side background position p+l<sub>2</sub> with intensity B<sub>2</sub>.
- (5) If the background curve near the peak can be approximated by a straight line, the background intensity *B* at the peak position is calculated as

$$B = (B_1 l_2 + B_2 l_1) / (l_1 + l_2)$$
(18)

The background intensity, B, at the candidate peak position is estimated by adding the fractional background intensities from both sides of the peak,  $B_1$  and  $B_2$ , which are inversely proportional to the distances



Fig. 3. Schematic diagram of a peak position and its background at both sides of the peak.

<sup>\*</sup>The typical full width at half maximum of the average peak : refer to 3.1.

from the peak to both sides of background positions  $l_1$  and  $l_2$ .

Let *P* denote the peak intensity with the background and *N* the net peak intensity, then, *N*=*P*-*B*, and the variance  $\sigma_N^2$  of *N* is calculated as follows [5]:

$$\sigma_N^2 = \sigma_p^2 + \sigma_B^2, \qquad (19)$$

where

$$\sigma_p^2 = P, \quad \sigma_{B1}^2 = B_1, \quad \sigma_{B2}^2 = B_2,$$
 (20)

and

$$\sigma_B^2 = [l_2/(l_1 + l_2)]^2 \sigma_{B1}^2 + [l_1/(l_1 + l_2)]^2 \sigma_{B2}^2, \quad (21)$$

then,  $\sigma_N^2$  is calculated as follows:

$$\sigma_N^2 = P + \left( B_1 l_2^2 + B_2 l_1^2 \right) / \left( l_1 + l_2 \right)^2$$
(22)

Therefore, the peak decision condition is given as follows:

$$N > k\sigma_N \tag{23}$$

If the second derivative curve does not cross the horizontal axis within a distance of 3 times the peak width (full width at half maximum of a typical peak) from the candidate peak position on both sides of the peak, we accept the position with a distance of 3 times the peak width from the candidate peak position as a background position for the peak.

#### 4. Some practical examples

#### 4.1. General

Some practical examples applied to the typical spectra of AES and XPS using codes written for computing are shown for the three peak detection methods. Fig. 4. Figures 5 and 6 show AES spectra, Figs. 7-9 show XPS spectra. Each processing condition is shown below, where *T*, *Bsmp*, *Smp*, *Step* and *Typw* stand for the total sampling points, smoothing points of background, smoothing points of spectrum, sampling step width and typical peak width of the spectrum, respectively, and *k* is the critical value shown in each peak detection formula.

#### 4.2. Processing conditions

#### 4.2.1. AES spectrum

*T*=2001, *Step*=1 eV, *Typw*=20 eV Figure 4: *Bsmp*=31, *k*=2.5 Figure 5: *Smp*=13, *k* =1.4 Figure 6: *Smp*=13, *k* = 2.5

#### 4.2.2. XPS spectrum

*T*=1001, *Step*=1 eV, *Typw*=10 eV Figure7: *Bsmp*=31, *k*=3 Figure 8: *Smp*=7, *k*=2.5 Figure 9: *Smp*=11, *k*=3

#### 5. Summary

#### 5.1. Relative merits of each method

Proposed peak detection methods for a spectrum are not fully perfect but if the parameters such as *Smp*, *Bsmp*, *Step* and *Typw* for the detecting algorithms are given properly in automatic computing, finely good results are obtained for practical uses as shown in Figs.4-9. Summarized relative merits of each method are shown in Table 1.

#### 6. Acknowledgement

The author would like to thank Dr. Yoshitaka Nagatsuka for developing these peak detection algorithms. Local members of TC201SC3WG4 in Japan are also acknowledged for their developing codes for computing and useful advice and fruitful discussion.

#### 7. References

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Kind of peak	Peak detection method	Results
(1) Single small peak	1. Background estimation	Almost good
	2. 2nd derivative	Sometimes neglects broad peaks
	3. Peak and Background relations	Sometimes neglects broad peaks
(2) Single large peak	1. Background estimation	Good
	2. 2nd derivative	Sometimes finds spurious peaks at peak base
	3. Peak and Background relations	Good
(3) Grouped small peaks	1. Background estimation	Sometimes neglects small peaks
	2. 2nd derivative	Sometimes neglects broad peaks
	3. Peak and Background relations	Sometimes neglects small peaks
(4) Shoulder peak	1. Background estimation	Not appropriate
	2. 2nd derivative	Sometimes neglects shoulder peak
	3. Peak and Background relations	Sometimes neglects shoulder peak

Table 1 Relative merits of each method.

Notes

Names of Peak detection method in Table1 are short for followings.

1. Background estimation: Peak Detection Using Rough Estimation of Spectrum Background in 3.1.

2. 2nd derivative: Peak Detection Using Threshold Curve of Second Derivative in 3.2.

3. Peak and Background relations: Peak Detection by Directly Calculating Peak and Background Relations at the Candidate Peaks in 3.3.





Fig. 4. (a) Example of AES peak detection using the method shown in 3.1. (b) Noise threshold curve of the above peak detection.





Fig. 5. (a) Example of AES peak detection using the method shown in 3.2. (b) Second derivative curve of the above peak detection.





Fig. 6. (a) Example of AES peak detection using the method shown in 3.3. (b) Second derivative curve of the above peak detection.





Fig. 7. (a) Example of XPS peak detection using the method shown in 3.1. (b) Noise threshold curve of the above peak detection.



Fig. 8. (a) Example of XPS peak detection using the method shown in 3.2.(b) Second derivative curve of the above peak detection.





Fig. 9. (a) Example of XPS peak detection using the method shown in 3.3. (b) Second derivative curve of the above peak detection.

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#### 査読コメント

#### 査読者 1. 吉原一紘(アルバック・ファイ)

ピーク位置の判定に関する汎用性のあるアルゴリズムの提案は実用上重要な課題ですので,掲載に値すると思いますが,いくつか初歩的なことで不明な 点がありましたので,お教え頂ければ幸いです.

#### [査読者 1-1]

ピークディテクションの第1の方法としてあげら れているスペクトルのバックグラウンドを見積もる 方法ですが,(1)式で記述されているバックグラウン ドの定義はあるデータ点(*i*)のバックグラウンド $b_i$ はそのデー点の周りの 2m+1点の平均と見なすとい うことのように思えます.もしそうならば, $y_{i+j}$ の variance は以下のようになります.

$$\frac{\sum_{j=-m}^{m} (y_{i+j} - b_i)}{2m}$$

この式は直ちには(3)式にはならないような気がし ます.

#### [著者]

AESやXPSの計測は電子1個1個を計測しますか ら計数値は整数となります.一方,分光法や液体ク ロマトグラフ装置やガスクロマトグラフ装置からの 出力はアナログ扱いとなり測定値は実数です.後者 の測定値はガウス分布(正規分布)となりますが、 前者の計数値は Poisson 分布に従います. Poisson 分 布に従う計数値の標準偏差は計数値(期待値)の平 方根と表され,また分散(Variance)は標準偏差の二 乗ですから計数値(期待値)そのものとなります. また期待値は複数測定値の平均値で表されます.従 いまして(1)式の BG 値の分散は、係数の h<sub>i</sub>が2 乗と なるもの,基本的には計数値そのもので表します. 逆に言えば分散 (Variance) が上式のように書けると いうのは実は、その統計事象がランダムで正規分布 に従うことを暗黙に仮定しています. 電子計測の場 合には,計測値の分布は正規分布ではなく,厳密に は Poisson 分布であり、分散の2 乗が平均値になる という事実だけを用いていますので、(3)式の方が上 式よりも厳密に成り立つ式になります.

#### [査読者 1-2]

また,ここで covariance に関する議論があります が,結局は covariance=0 としているので気にする必 要は無いのかもしれませんが,同一スペクトル上で のデータ点の間の covariance という意味が分かりま せん. なお, m の値はどのように設定するのでしょうか.

#### [著者]

Covariance とは単純にデータ点間の相関という意 味です. ランダム実験におけるランダムデータの誤 差が Variance と Covariance で書けることは, References で引用しております Peter Gans, "Data Fitting in the Chemical Sciences" Wiley, (1992)に書か れています. 全くのランダムな事象ではない限り厳 密には相関は0にはなりませんが、少なくともデー タのノイズ成分には相関がないことは明らかですの で、Variance に比べて、Covariance の寄与は少ない と仮定して0としています. 逆に言えば、この寄与 が0にならないと、この問題を扱う手立てがなく なってしまいます.しかし、この定式化では共分散 が評価できないからそれを 0 にするというのも乱 暴な話ですので、データの取得方法が独立である、  $\neg \sharp \vartheta$ , Further, each  $y_i$  is measured independently, and may have no correlation with each other, then:と修正し ました.

また, *m*の値の決め方については, 2*m*+1 が取り得る幅を AES や XPS で得られる標準的な半値幅の数倍となるように決めます.本文中に記述します.

#### [査読者 1-3]

ピークディテクションの第3の方法としてあげら れている2次微分を用いる方法ですが,この方法は 南茂夫先生著の「科学計測のための波形データ処理」 に記述があります.南先生は「実際の観測波形では 無数の極大値が発生するので,平滑化微分の点数の 選択が重要であり,雑音の分散に応じてその範囲を 変化させる必要がある.」と指摘しています.ここで は *p-3w<x<p* の範囲で極値を探すという記述があり ますが,南先生が指摘されるように,その間に発生 する無数の local maximum/minimum をどのように排 除するのかを記述していただければと思います.

#### [著者]

2 次微分に閾値を設定して判定しています.ただ し、実際には、再度 Peak と Background の比を使っ てピークの存在を再確認しますので、閾値の係数は 第2の方法としてあげている2次微分法に比べ 1/3 に小さくし、出来うる限りピークを拾う様にしてい ます.

一方,微分点数を変化させることも考えられます が,微分点数を小さく(または大きく)すると,そ れにつれてノイズの(平均)分散曲線も変わります.

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従って,最適には微分点数がそのピークの半値幅程 度になるように選ぶことになります.

#### [査読者 1-4]

ピークディテクションの第2の方法としてあげら れている2次微分に閾値を設定して判定する方法は、

[査読者 1-3] で述べた望まない極値を排除する方 法になるのでしょうか.

#### [著者]

上記 [査読者 1-3] に対する見解と同じです.

#### [査読者 1-5]

(17)式の  $g_i$ は Savitzky-Golay の係数ですから  $d_i$ は 微分値です. 第1の方法の場合は  $b_i$ が平均値でした から, variance の意味は理解できましたが, variance が 平均からのずれを示す値だとすると,  $y_{i+j}$ の variance と  $d_i$ の variance は(21)式に示されているよう には直接には結びつかないように思えます.

#### [著者]

微分すると background は消えますので $d_i$ の項のみ となります.その後の統計的な処理に対する考え方 は、Poisson 分布に従う計数値の取り扱いになります ので、[査読者 1-1]に対する説明と同じになります.

#### [査読者 1-6]

「バックグラウンド」について、(3)式は、計数値 Nの誤差が $\sqrt{N}$ になることを示しており、この式自 体にはもちろん問題はありません.ただし、この論 文では計数値の回りの 2m+1 個の平均点をとったも のをバックグラウンドとしています. ある計数値の 回りの 2m+1 個のデータの平均をとると言うことは, 2m+1 個のエネルギーの違った箇所でのデータを足 しあわせてその平均をとることですので、得られた バックグラウンドとしての値の誤差には各データ点 のポアソン分布に起因する計数誤差だけではなく, 測定したエネルギー値の誤差に起因する計数値の誤 差も含まれると思われます. variance を(3)式で取り 扱うためには、「あるデータ点の周りの 2m+1 個の データ点の平均をそのデータ点のバックグラウンド とする」ということと「期待値は複数測定値の平均 で表される」ということを結びつける説明をしてい ただくことが必要ではないでしょうか.

#### [著者]

ここでいうバックグラウンドとは本当のバックグ ラウンドではなく、ピークを検出するためだけの仮 のバックグランドですから、大雑把で良いと考えて います.ピークが適当に潰れてくれれば十分目的を 果すことができます.また,測定したエネルギー値 の誤差に起因する計数値の誤差も含まれることは確 かにあり得ますが,ここでは単純にカウントの計測 値にのみ起因する誤差によってピークの有無を判断 することを考えています.エネルギー値の誤差に起 因する計数値の誤差を考えても,その寄与はカウン トの計測値にのみ起因する誤差に比べてかなり小さ いと思われます.

一方,ご指摘の様に,バックグラウンドなどの計 測値がポワソン分布に従う場合の取り扱い方の特徴 を記述した方が良いと思われますので,(1)式の後に 追記しました.

#### [査読者 1-7]

Fig. 1 について,私の方で作図をしてみますと Fig. 1 のようにはなりません. N<sub>i</sub>の XPS データ(1 eV ス テップで取得)を使って(1)式に基づいて, m=15 の 場合について作図してみました.下図(Fig. Q&A-1) をご参照ください.(論文では XPS のピークの標準 FWHMを10 Vとし,その数倍を 2m+1 点とすると 記述されていますので, m=15 としました.)バック グラウンドがピーク内に入り込んでいる場合もあり, Fig. 1 とはかなり異なった挙動の図が得られていま す.

また、大きいピークの近傍では、ピークに引きず られバックグラウンドがかなり上昇しています. し たがって、ピークの近傍に出現する小さなピークは バックグラウンドよりも小さくなり、 判定されませ ん. また, このバックグラウンドに(7)式で定義され る分散を重ねますと(ここでは(7)式のkの値は3と しています), 下図 (Fig. O&A-2) が得られます. (分 散の影響が小さいため一部を拡大しました. バック グラウンドに標準偏差を加えた値を紫色の線で書き ましたが,ほぼ重なってしまいました.) このスペク トルに固有な事象かもしれませんが、標準偏差を足 してもバックグラウンドの位置はほとんど変わらず, Fig. 1 のような分散の影響は現れませんでした. な お,上図からは,2連のピークの「valley」の上にバッ クグラウンドが入り込み, Fig. 1 に示される 2 連ピー クの場合とはかなり挙動が異なっています.

この曲線を通常の意味でのバックグラウンドと見 なすことは少し無理があるのではないでしょうか. 本論文では「バックグラウンド」の定義は,3.1.節に 記述してありますが, [査読者 1-6]の質問に対する



Fig. Q&A-1.



Fig. Q&A-2.

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ご説明も含め、定義内容を少し加筆していただけれ ば理解が進むのではないかと思います.

#### [著者]

本アルゴリズムをプログラム作成により再現戴き 有り難うございます.アルゴリズム通りのバックグ ランド表示となっていますので,アルゴリズムの検 証になっています.Fig.1の作図イメージが実際と 異なる件ですが,アルゴリズムを理解していただく ために誇張して描画しております.誇張しすぎない 様に少し修正しました.実際の描画はFig.4(b),Fig. 7(b)で具体的に表示されています.確かに*b<sub>i</sub>*+*k*σは*b<sub>i</sub>* より少し大きく表示されています.カウント数の高 い領域では閾値線はバックグラウンドより更に上に なると思われます.また計数値の大きさでバックグ ラウンドから離れる程度が異なってきます.

また2つのピークの谷底付近の閾値線の挙動です が、ご呈示戴いた2つのピークは分離が良く、谷底 がバックグランド近くまで落ち込んでいますので、 閾値線は図示された位置にくると思われます.分離 が悪い場合ですとFig.1の様になることが期待され ます.

## 査読者 2. 城昌利(AIST)

#### [査読者 2-1]

It is more convenient to remind the readers that Eqs. (3) and (19) are the direct conclusions from the property of Poisson distribution.

#### [著者]

Next phrase, "which obeys statistical theory based on the Poisson distribution" is inserted after the phrase, "If the random nature of the spectrum data  $y_i$ ".

#### [査読者 2-2]

In 3.2., the authors define the  $p_1$  and  $p_2$  as the points at the second derivative's local maxima. Are they more suitable than the zero-cross points, the inflection points?

## [著者]

The  $p_1$  and  $p_2$  as the points at the second derivative's local maxima correspond to a flat position of background on both sides of a peak or flat point of valley between peaks. As red dotted line in Fig. 3 is distorted, it is modified a little to appropriate shape. It seemed hard correction for author to modify the second derivative curve perfectly this time.

#### [査読者 2-3]

In 3.1., I don't understand why they don't use the width *w* deduced in 3.2. for examining *S*. Obviously  $w=(p_2-p_1)/2$ , or (distance between inflection points) seems to be a better estimate for FWHM.

#### [著者]

The use of the typical full width at half maximum of the average peak as a default values is the feature of these three peak detection methods. For example, 20 eV for AES and rather big figure, 10 eV, for XPS are allowed to adopt as default values. As it is difficult to know any full width at half maximum or to calculate it before detecting peak, a default value is adopted in these three algorithms. Although the use the full width at half maximum deduced in 3.3. become possible only after detecting peaks or detecting candidate peaks, it is impossible to use the values before detecting peaks.

#### [査読者 2-4]

In addition to comment [査読者 2-3], it seems better to unify these three methods to give a best one. Is there a special reason to leave them separately? At least when the authors write codes, they should do so.

#### [著者]

Unfortunately the combination of these three methods constitutes an infringement of the patents.

#### [査読者 2-5]

As long as one needs to supply values such as *Smp*, *Bsmp*, *Step*, and to check the appropriateness of the result, there is not much practical difference between the present method and such conventional visual inspections by human eyes. Do you think if it is possible, in the future, to write a complete and automatic code that works without human aid, which is the ultimate purpose of this paper?

#### [著者]

It is hard to find a proper resolution of this comment. Some answer to this comment is given in "1.Introduction". As far as there may be no perfect method, analysts should find the best way by checking the performance of peak detecting method interactively with computer.

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## [査読者 2-6]

3 つの方法が特許のために統合できないとのこと ですが([査読者 2-4] 参照),それなら該当する特 許を引用してください.この論文を読むと,誰でも, 統合するのが一番よいと気づくと思いますが,それ ができないのでは,発表する意味が何なのかわから ず小生は困惑しました.特許が絡むとすると,これ らを利用することも躊躇されます.もちろん,これ らを利用した製品を売ってはいけないということで, 読者が研究用としてこれを発展させるのは自由と解 釈できますが,それでよいですか.権利が絡むのな ら,このあたり,明確に書いておく必要があると思 います.

#### [著者]

関連特許について引用しました.特許に関する注 意事項まで記述しなくとも,その意味は常識的に言 外に読み取って戴くことで十分と思われます.また 本発表の目的は3種のアルゴリズムを個別に紹介す ることにあります.これらの手法のそれぞれの組み 合わせ方も考えられますし,読者が組み合わせて使 用することも可能ですが,それは次の段階のプロセ スと思われます.

### [査読者 2-7]

[査読者 2-3]の回答について、wは一度ピークを 検出した後でないと、わからないから、検出には使 えないとの回答は納得しかねるものがあります. ど の方法も、フィルターをかけて得た量と元の量を比 較する、という、複数の操作からなるわけで、wを 求めるのはさらに 1 手順加わるに過ぎないのではな いでしょうか?とくに 3.2.では  $p_1$ ,  $q_1$ , 等, ほとんど wを求めるのに等しい議論をしているのでは思いま すが.たとえば, ( $p_1$ ,  $p_2$  と同様に直ちに, 求まる)  $r_1$ ,  $r_2$ を変曲点の位置として, wの代わりに, ( $r_1$ - $r_2$ ) を用いて議論するのではなぜいけないのでしょうか.

## [著者]

ピークがすべて理想的な Gaussian や Lorentzian に なっていれば,変曲点の位置を使って,wを求める ことは可能です.しかし実際にはそのような誰の目 で見ても分るピークをピークと判定できるのは当然 のことで、実際にはピークかノイズかどちらにでも 取れるようなギリギリの状態のピークを計算機で判 定することに意義があり,また理論的な半値幅も-桁以上違っていることがしばしばあります. このよ うな場合を考えますと、検出したピークのすべてに ついて半値幅 w を求め、それによってピークの検出 条件を変えても結果的には大して変わりません.ま た実際には、スペクトルの平滑化や微分曲線を求め る際に、途中で計算点数(wから求める)を変える ことができません.もし無理に変えるとそこでこれ らの曲線には段差がついてしまい、その段差のため に全く存在しないピークをピークと判定してしまう 危険性が大いにあります. このような事情から,常 識的に考えると一見ピーク検出を行なう際に半値幅 を求めて行う手法は良い様に思われますが、実際に は殆ど効果を発揮できません. 逆効果さえ出てしま います.